

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>	<b>ATTY. DOCKET NO.</b> 113337	<b>SERIAL NO.</b> TBA
	<b>APPLICANTS</b> BRAND et al.	
	<b>FILING DATE</b> Concurrently herewith	<b>GROUP</b> TBA 2128

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**U. S. PATENT DOCUMENTS**

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE
	5,465,321	11/7/95	Smyth	395	22	4/7/93

**FOREIGN PATENT DOCUMENTS**

EXAMINE R INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLAS S	SUBCLA SS	TRANSLATION	
						YES	NO

**OTHER DOCUMENTS**

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
T.P.	Chun Kin Chan et al: "Sequential Sampling Plans for Early-Life Reliability Assessment, Annual Reliability and Maintainability Symposium, 1997 Proceedings, Philadelphia, PA, 1997 January 13-16, ISSN 0149-144X, pp. 131-135

<b>EXAMINER</b> Thai Phan	<b>DATE CONSIDERED</b> 9/14/04
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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